

<b>Notice of References Cited</b>	Application/Control No. 10/540,121		Applicant(s)/Patent Under Reexamination DUDECK ET AL.	
	Examiner Shelley Chen		Art Unit 3661	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2,906,355 A	09-1959	HIRSCH GEORGE B	180/204
*	B	US-3,029,884 A	04-1962	CLEMENTS JOHN A; et. al.	180/204
*	C	US-3,073,407 A	01-1963	YATES JOHN W; et. al.	180/204
*	D	US-3,097,717 A	07-1963	GILVARRY JOHN J; et. al.	180/204
*	E	US-3,117,642 A	01-1964	LARINOFF MICHAEL W	180/204
*	F	US-4,931,930 A	06-1990	Shyu et al.	701/36
*	G	US-5,742,141 A	04-1998	Czekaj, James L.	318/587
*	H	US-2001/0030688 A1	10-2001	Asahi et al.	348/118
*	I	US-2002/0041239 A1	04-2002	Shimizu et al.	340/932.2
*	J	US-2002/0084916 A1	07-2002	Shimizu et al.	340/932.2
*	K	US-2002/0104700 A1	08-2002	Shimazaki et al.	180/204
*	L	US-6,483,442 B2	11-2002	Shimizu et al.	340/932.2
*	M	US-6,476,730 B2	11-2002	Kakinami et al.	340/932.2

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 2075251 A1	09-2002	World Intellect	LACEY et al.	G01C 21/20
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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Application/Control No.

10/540,121

Applicant(s)/Patent Under  
Reexamination  
DUDECK ET AL.

Examiner

Shelley Chen

Art Unit

3661

Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0080877 A1	05-2003	Takagi et al.	340/932.2
*	B	US-2003/0121706 A1	07-2003	Yamada et al.	180/204
*	C	US-6,611,744 B1	08-2003	Shimazaki et al.	701/41
*	D	US-6,657,555 B2	12-2003	Shimizu et al.	340/932.2
*	E	US-6,697,720 B2	02-2004	Ikeda, Atsushi	701/36
*	F	US-2004/0064249 A1	04-2004	Lacey et al.	701/207
*	G	US-6,820,711 B2	11-2004	Yamada et al.	180/204
*	H	US-2004/0249564 A1	12-2004	Iwakiri et al.	701/200
*	I	US-2004/0254719 A1	12-2004	Tanaka et al.	701/200
*	J	US-2004/0254720 A1	12-2004	Tanaka et al.	701/200
*	K	US-6,892,134 B2	05-2005	Lacey et al.	701/209
*	L	US-2005/0163343 A1	07-2005	Kakinami et al.	382/103
*	M	US-2005/0203704 A1	09-2005	Frank et al.	701/300

**FOREIGN PATENT DOCUMENTS**

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	N					
	O					
	P					
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Shelley Chen

Art Unit

3661

Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0236201 A1	10-2005	Spannheimer et al.	180/204
*	B	US-7,012,548 B2	03-2006	Ishii et al.	340/932.2
*	C	US-7,076,345 B2	07-2006	Tanaka et al.	701/28
*	D	US-7,099,758 B2	08-2006	Tanaka et al.	701/36
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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